

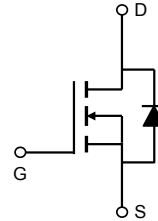
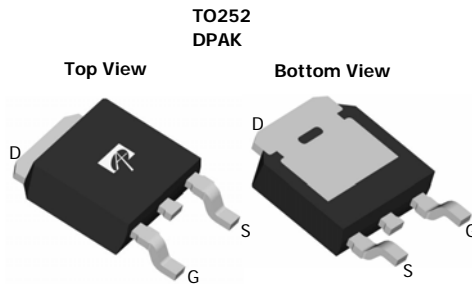
General Description

The AOD4182 is fabricated with SDMOS™ trench technology that combines excellent $R_{DS(ON)}$ with low gate charge and low Q_{rr} . The result is outstanding efficiency with controlled switching behavior. This universal technology is well suited for PWM, load switching and general purpose applications.

Product Summary

| | |
|---------------------------------|------------------|
| V_{DS} | 80V |
| I_D (at $V_{GS}=10V$) | 53A |
| $R_{DS(ON)}$ (at $V_{GS}=10V$) | < 15.5m Ω |
| $R_{DS(ON)}$ (at $V_{GS}=7V$) | < 20m Ω |

100% UIS Tested
 100% R_g Tested



Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

| Parameter | Symbol | Maximum | Units |
|--|------------------|-------------------------|------------------|
| Drain-Source Voltage | V_{DS} | 80 | V |
| Gate-Source Voltage | V_{GS} | ± 25 | V |
| Continuous Drain Current | I_D | $T_C=25^\circ\text{C}$ | 53 |
| | | $T_C=100^\circ\text{C}$ | 38 |
| Pulsed Drain Current ^C | I_{DM} | 85 | A |
| Continuous Drain Current | I_{DSM} | $T_A=25^\circ\text{C}$ | 8.5 |
| | | $T_A=70^\circ\text{C}$ | 6.8 |
| Avalanche Current ^C | I_{AS}, I_{AR} | 45 | A |
| Avalanche energy $L=0.1\text{mH}$ ^C | E_{AS}, E_{AR} | 101 | mJ |
| Power Dissipation ^B | P_D | $T_C=25^\circ\text{C}$ | 100 |
| | | $T_C=100^\circ\text{C}$ | 50 |
| Power Dissipation ^A | P_{DSM} | $T_A=25^\circ\text{C}$ | 2.5 |
| | | $T_A=70^\circ\text{C}$ | 1.6 |
| Junction and Storage Temperature Range | T_J, T_{STG} | -55 to 175 | $^\circ\text{C}$ |

Thermal Characteristics

| Parameter | Symbol | Typ | Max | Units |
|--|-----------------|--------------|-----|--------------------|
| Maximum Junction-to-Ambient ^A | $R_{\theta JA}$ | 16 | 20 | $^\circ\text{C/W}$ |
| Maximum Junction-to-Ambient ^{A D} | | Steady-State | 40 | 50 |
| Maximum Junction-to-Case | $R_{\theta JC}$ | 1 | 1.5 | $^\circ\text{C/W}$ |

Electrical Characteristics (T_J=25°C unless otherwise noted)

| Symbol | Parameter | Conditions | Min | Typ | Max | Units |
|-----------------------------|--|---|------|--------------|------------|-------|
| STATIC PARAMETERS | | | | | | |
| BV _{DSS} | Drain-Source Breakdown Voltage | I _D =250μA, V _{GS} =0V | 80 | | | V |
| I _{DSS} | Zero Gate Voltage Drain Current | V _{DS} =80V, V _{GS} =0V T _J =55°C | | | 10 50 | μA |
| I _{GSS} | Gate-Body leakage current | V _{DS} =0V, V _{GS} = ±25V | | | 100 | nA |
| V _{GS(th)} | Gate Threshold Voltage | V _{DS} =V _{GS} , I _D =250μA | 2.8 | 3.3 | 4.2 | V |
| I _{D(ON)} | On state drain current | V _{GS} =10V, V _{DS} =5V | 85 | | | A |
| R _{DS(ON)} | Static Drain-Source On-Resistance | V _{GS} =10V, I _D =20A T _J =125°C | | 12.5 22.5 | 15.5 28 | mΩ |
| | | V _{GS} =7V, I _D =20A | | 16 | 20 | mΩ |
| g _{FS} | Forward Transconductance | V _{DS} =5V, I _D =20A | | 33 | | S |
| V _{SD} | Diode Forward Voltage | I _S =1A, V _{GS} =0V | | 0.7 | 1 | V |
| I _S | Maximum Body-Diode Continuous Current ^G | | | | 54 | A |
| DYNAMIC PARAMETERS | | | | | | |
| C _{iss} | Input Capacitance | V _{GS} =0V, V _{DS} =40V, f=1MHz | 1335 | 1670 | 2005 | pF |
| C _{oss} | Output Capacitance | | 150 | 215 | 280 | pF |
| C _{riss} | Reverse Transfer Capacitance | | 40 | 72 | 100 | pF |
| R _g | Gate resistance | V _{GS} =0V, V _{DS} =0V, f=1MHz | 0.35 | 0.75 | 1.2 | Ω |
| SWITCHING PARAMETERS | | | | | | |
| Q _g (10V) | Total Gate Charge | V _{GS} =10V, V _{DS} =40V, I _D =20A | 22 | 28 | 34 | nC |
| Q _{gs} | Gate Source Charge | | 8.8 | 11 | 13 | nC |
| Q _{gd} | Gate Drain Charge | | 5 | 8 | 11 | nC |
| t _{D(on)} | Turn-On DelayTime | V _{GS} =10V, V _{DS} =40V, R _L =2Ω, R _{GEN} =3Ω | | 12 | | ns |
| t _r | Turn-On Rise Time | | | 9 | | ns |
| t _{D(off)} | Turn-Off DelayTime | | | 20 | | ns |
| t _f | Turn-Off Fall Time | | | 8 | | ns |
| t _{rr} | Body Diode Reverse Recovery Time | I _F =20A, dI/dt=500A/μs | 14.5 | 21 | 27.5 | ns |
| Q _{rr} | Body Diode Reverse Recovery Charge | I _F =20A, dI/dt=500A/μs | 45.5 | 65 | 85 | nC |

A. The value of R_{θJA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with T_A=25°C. The Power dissipation P_{DSM} is based on R_{θJA} and the maximum allowed junction temperature of 150°C. The value in any given application depends on the user's specific board design, and the maximum temperature of 175°C may be used if the PCB allows it.

B. The power dissipation P_D is based on T_{J(MAX)}=175°C, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Repetitive rating, pulse width limited by junction temperature T_{J(MAX)}=175°C. Ratings are based on low frequency and duty cycles to keep initial T_J=25°C.

D. The R_{θJA} is the sum of the thermal impedance from junction to case R_{θJC} and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of T_{J(MAX)}=175°C. The SOA curve provides a single pulse rating.

G. The maximum current rating is package limited.

H. These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with T_A=25°C.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

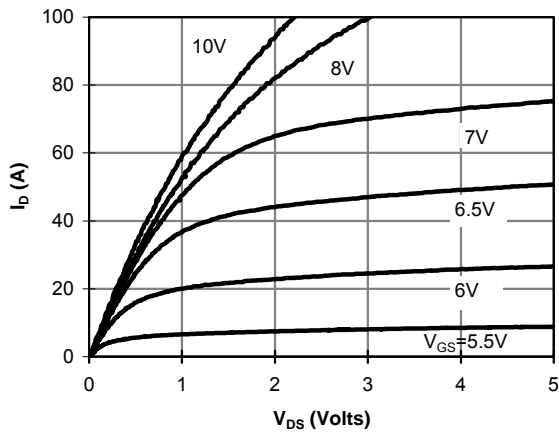


Fig 1: On-Region Characteristics (Note E)

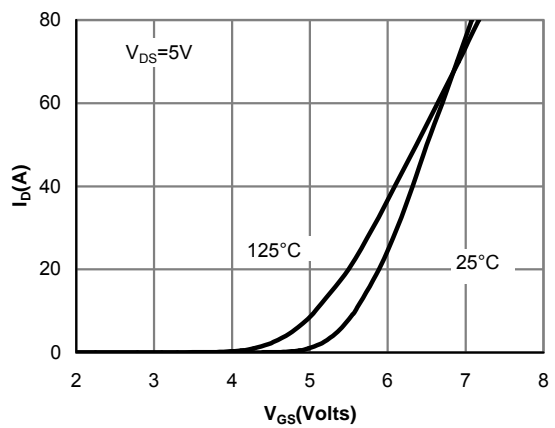


Figure 2: Transfer Characteristics (Note E)

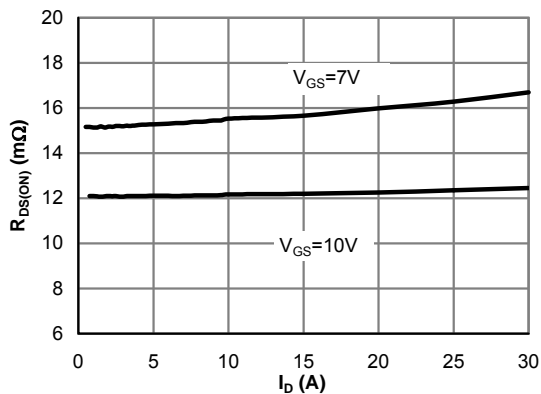


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

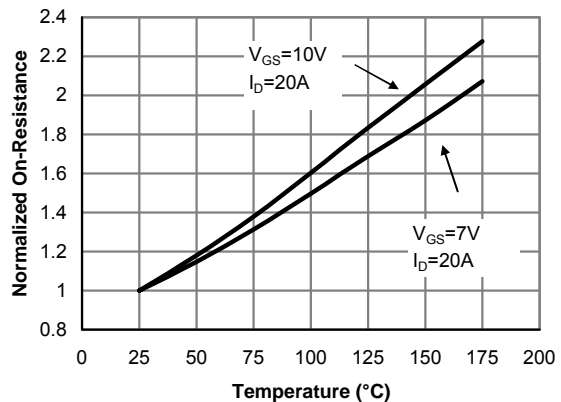


Figure 4: On-Resistance vs. Junction Temperature (Note E)

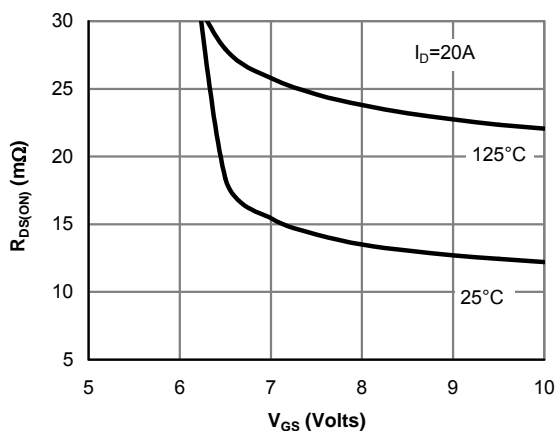


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

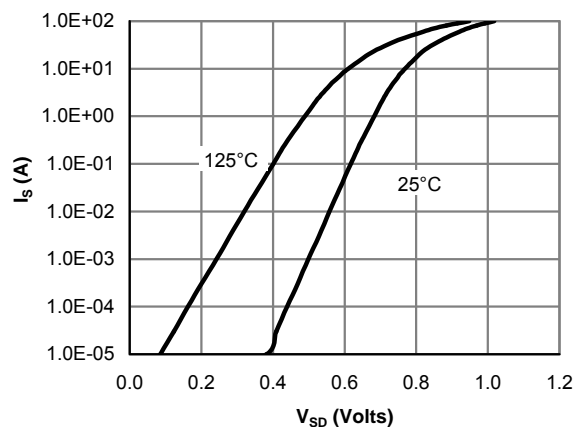


Figure 6: Body-Diode Characteristics (Note E)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

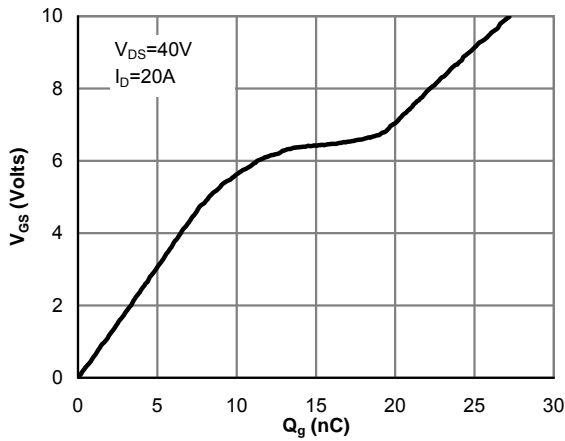


Figure 7: Gate-Charge Characteristics

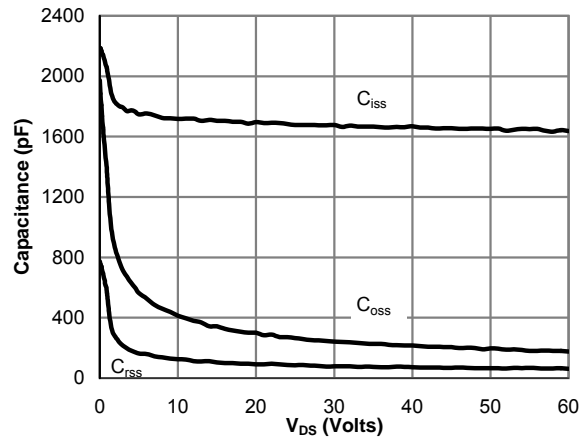


Figure 8: Capacitance Characteristics

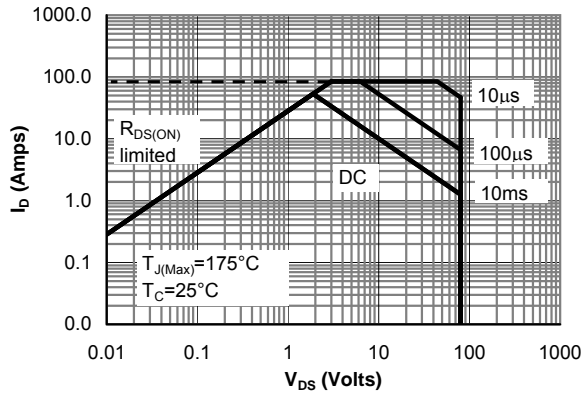


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

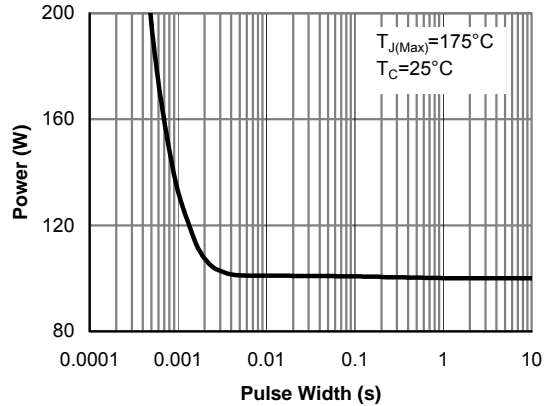


Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)

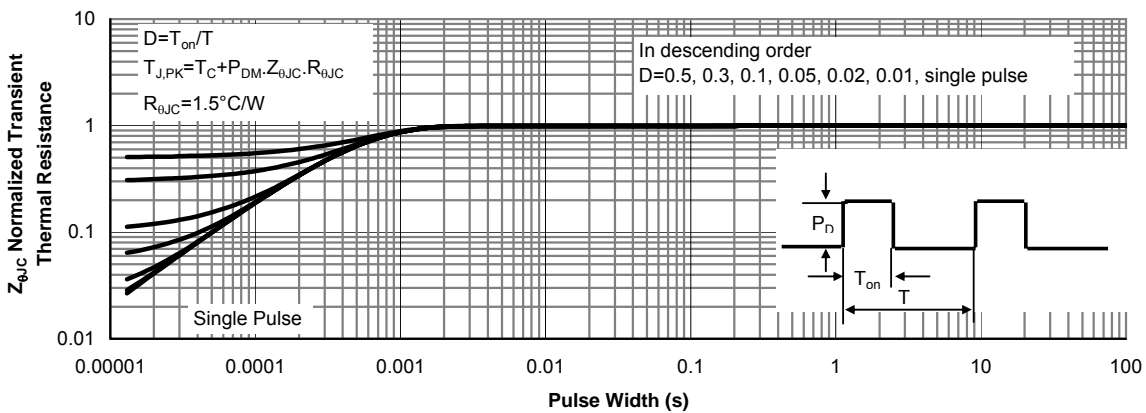


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

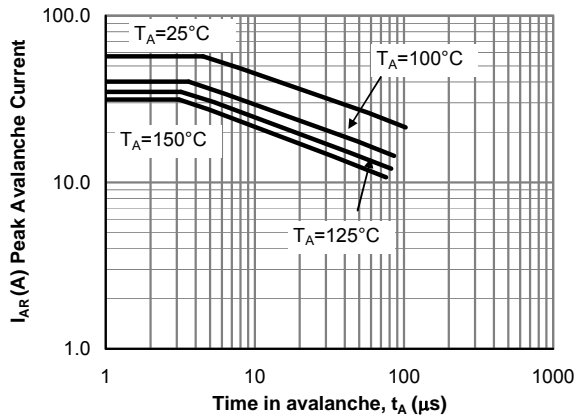


Figure 12: Single Pulse Avalanche capability (Note C)

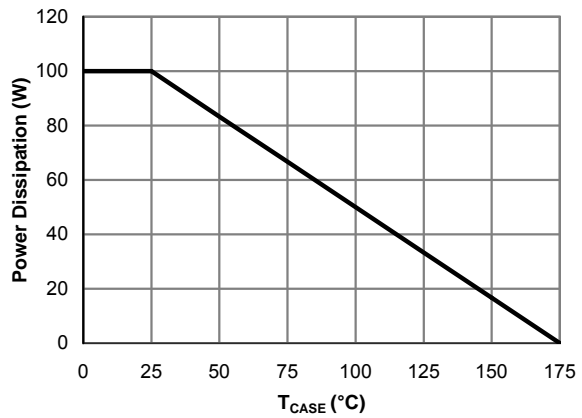


Figure 13: Power De-rating (Note F)

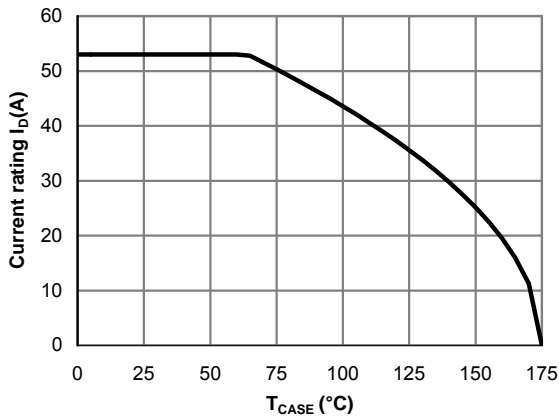


Figure 14: Current De-rating (Note F)

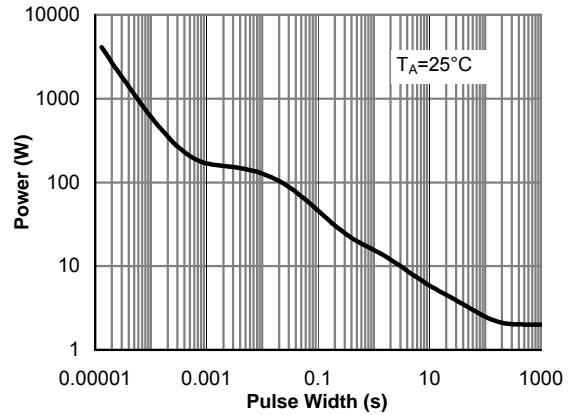


Figure 15: Single Pulse Power Rating Junction-to-Ambient (Note H)

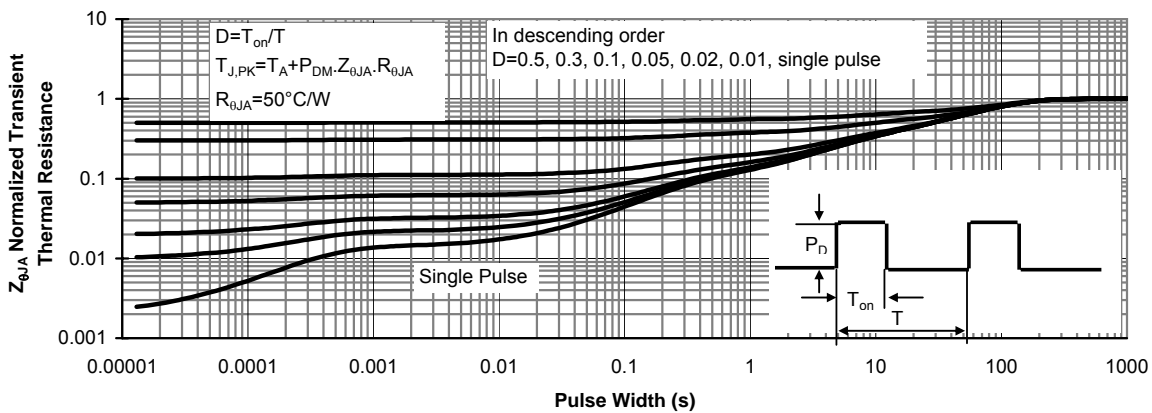


Figure 16: Normalized Maximum Transient Thermal Impedance (Note H)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

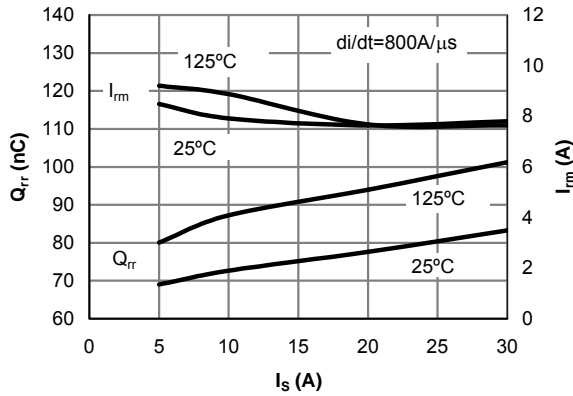


Figure 17: Diode Reverse Recovery Charge and Peak Current vs. Conduction Current

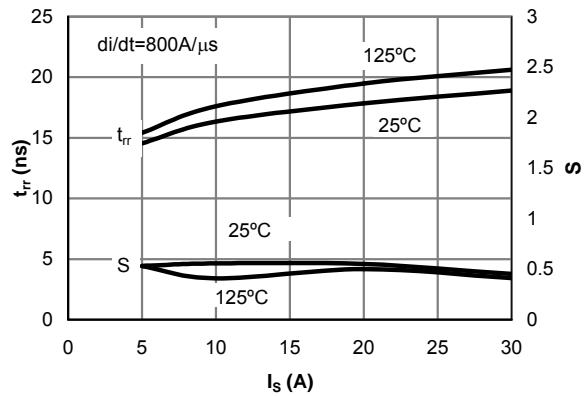


Figure 18: Diode Reverse Recovery Time and Softness Factor vs. Conduction Current

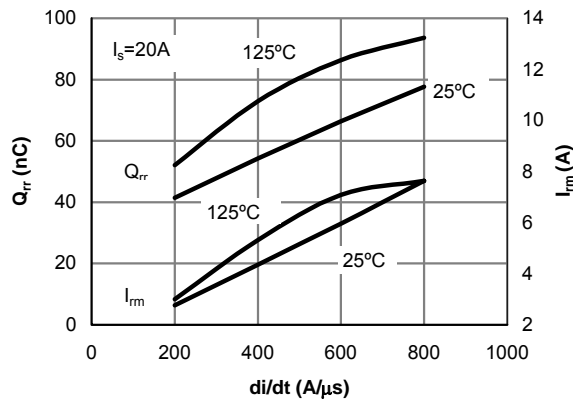


Figure 19: Diode Reverse Recovery Charge and Peak Current vs. di/dt

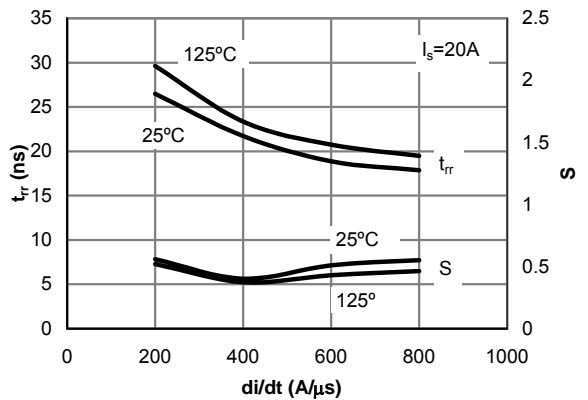
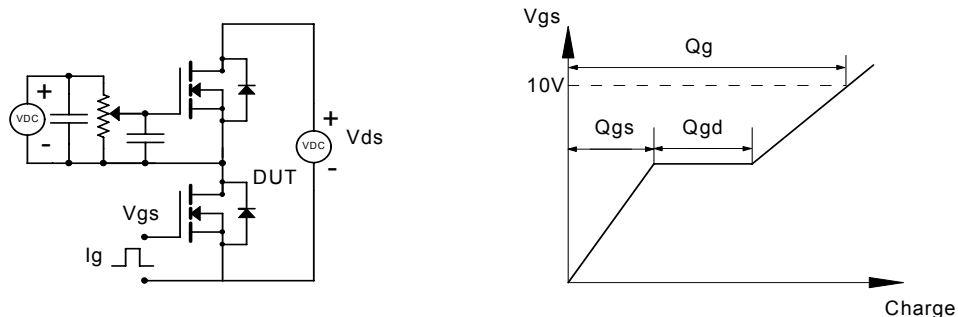
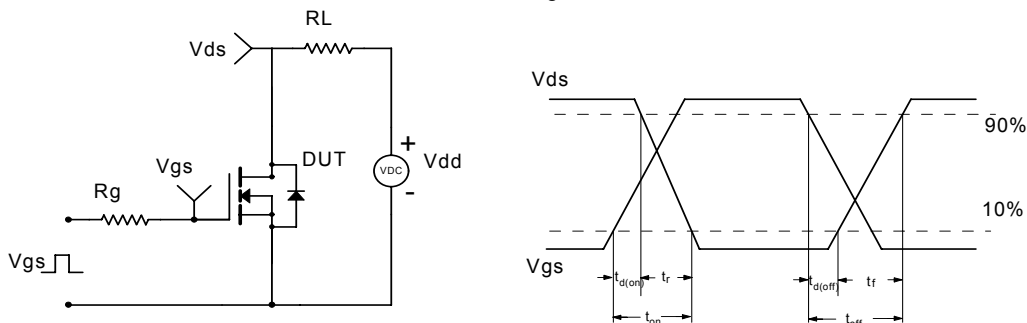


Figure 20: Diode Reverse Recovery Time and Softness Factor vs. di/dt

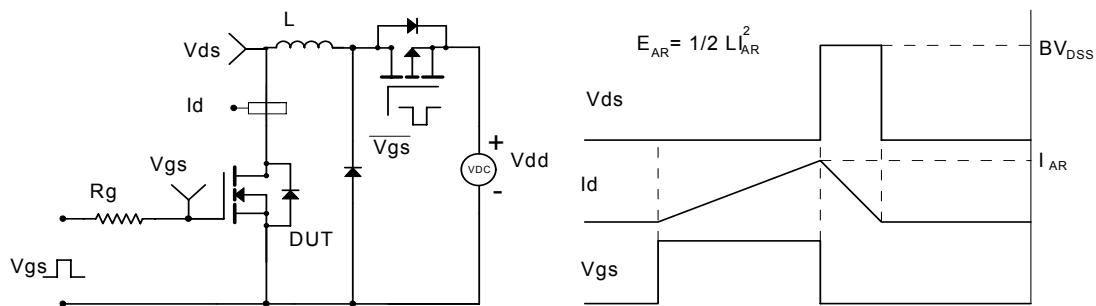
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

